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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant:

Martin David Smalc

Serial No.:

10/722,364

Filed:

November 25, 2003

For:

Thermal Solution For Electronic Devices

Group No.

2835

Attorney's Docket No.

P1085/N9961

Customer No.

23456

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Mail Stop Amendment Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Dear Sir:

Pursuant to 37 C.F.R. §1.56, applicant hereby calls to the attention of the Patent and Trademark Office the following patents and other documents which are listed on attached Form PTO-1449.

This Supplemental Information Disclosure Statement is being filed before the mailing date of a first Office Action on the merits for the above-referenced application.

- 1. Japan Unexamined Patent Publication JP2004023065A
- 2. Japan Unexamined Patent Publication JP2004023066A
- 3. DXX03-013 Tokugan 2003-382882, Application date Nov. 12, 2003
- 4. DXX03-022 Tokugan 2003-375005, Application date Nov. 4, 2003
- 5. DDXX03-031 Tokugan 2004-017710, Application date Jan. 26, 2004

Copies of the listed documents are attached.

For foreign references, English translations of non-English documents are enclosed.

Applicant respectfully requests that these references be considered by the Examiner and made of record as part of the "available prior art" under 37 C.F.R. §1.104.

The Commissioner is authorized to charge any deficiency or credit any overpayment in connection with this Supplemental Information Disclosure Statement to Deposit Account No. 50-1202.

Respectfully submitted,

James R. Cartiglia

Registration No. 30,738

WADDEY & PATTERSON

A Professional Corporation

Customer No. 23456

ATTORNEY FOR APPLICANT

James R. Cartiglia Waddey & Patterson 414 Union Street, Suite 2020 Bank of America Plaza Nashville, TN 37219 (615) 242-2400

CERTIFICATE OF FIRST CLASS MAILING

I hereby certify that this Supplemental Information Disclosure Statement (2 pages including Certificate of First Class Mailing); Form PTO-1449 (1 page); References (5); and return postage-paid self-addressed postcard are being deposited with the United States Postal Service as first class mail in an envelope addressed to:

Mail Stop Amendment Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

on June 2, 2004.

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R. Robin Avery

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Page 1 of 1

INFORMATION DISCLOSURE CITATION (Use several sheets if necessary) P1085/N9961 Customer No. 23456 Applicant Martin David Smalc	Comparable to	19	7:47 : TO L.	U.S. Department of Commerce Patent & Trademark Office		Atty. Docket No.			Serial No.		
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